











SN74AUP1G57

SCES503J - NOVEMBER 2003 - REVISED JUNE 2015

SN74AUP1G57 Low-Power Configurable Multiple-Function Gate

Features

- Available in the Texas Instruments NanoStar™ **Packages**
- Low Static-Power Consumption $(I_{CC} = 0.9 \mu A Maximum)$
- Low Dynamic-Power Consumption $(C_{pd} = 4.3 \text{ pF Typical at } 3.3 \text{ V})$
- Low Input Capacitance ($C_i = 1.5 pF Typical$)
- Low Noise Overshoot and Undershoot <10% of V_{CC}
- I_{off} Supports Partial-Power-Down Mode Operation
- Includes Schmitt-Trigger Inputs
- Wide Operating V_{CC} Range of 0.8 V to 3.6 V
- Optimized for 3.3-V Operation
- 3.6-V I/O Tolerant to Support Mixed-Mode Signal Operation
- $t_{pd} = 5.3$ ns Maximum at 3.3 V
- Suitable for Point-to-Point Applications
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- ESD Performance Tested Per JESD 22
 - 2000-V Human-Body Model (A114-B, Class II)
 - 1000-V Charged-Device Model (C101)

2 Applications

- Active Noise Cancellation (ANC)
- **Barcode Scanners**
- **Blood Pressure Monitors**
- **CPAP Machines**
- Cable Solutions
- E-Books
- **Embedded PCs**
- Field Transmitter: Temperature or Pressure Sensors
- HVAC: Heating, Ventilating, and Air Conditioning
- Network-Attached Storage (NAS)
- Server Motherboard and PSU
- Software Defined Radio (SDR)
- TV: High-Definition (HDTV), LCD, and Digital
- Video Communications Systems

3 Description

The SN74AUP1G57 device features configurable multiple functions. The output state is determined by eight patterns of 3-bit input. The user can choose the logic functions AND, OR, NAND, NOR, XNOR, inverter, and noninverter. All inputs can be connected to V_{CC} or GND.

Device Information⁽¹⁾

PART NUMBER	PACKAGE	BODY SIZE (NOM)
SN74AUP1G57YFP	DSBGA (6)	1.16 x 0.76 mm
SN74AUP1G57YZP	DSBGA (6)	1.388 x 0.888 mm
SN74AUP1G57DRY	SON (6)	1.00 x 1.45 mm
SN74AUP1G57DSF	SON (6)	1.00 x 1.00 mm
SN74AUP1G57DBV	SOT-23 (6)	2.80 x 2.90 mm
SN74AUP1G57DCK	SC70 (6)	2.10 x 2.00 mm
SN74AUP1G57DRL	SOT (6)	1.60 x 1.60 mm

(1) For all available packages, see the orderable addendum at the end of the data sheet.

Functional Block Diagram (Positive Logic)

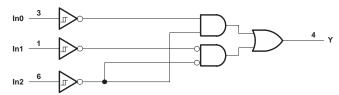




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4 Revision History

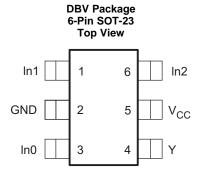
Changes from Revision I (May 2010) to Revision J

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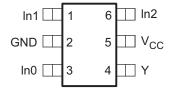
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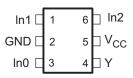
5 Pin Configuration and Functions



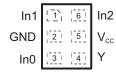




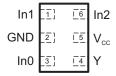
DRL Package 6-Pin SOT Top View



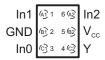
DRY Package 6-Pin SON Top View



DSF Package 6-Pin SON Top View



YFP Package 6-Pin DSBGA Top View



YZP Package 6-Pin DSBGA Top View

Pin Functions

	PIN								
NAME	SOT-23, SC70, SOT	DSBGA	I/O	DESCRIPTION					
ln1	1	A1	I	Logic input 1					
GND	2	B1	_	Ground					
In0	3	C1	ı	Logic input 0					
Υ	4	C2	0	Logic output					
V _{CC}	5	B2	_	Power					
ln2	6	A2	I	Logic input 2					

Product Folder Links: SN74AUP1G57



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

			MIN	MAX	UNIT
V _{CC}	Supply voltage		-0.5	4.6	V
VI	Input voltage ⁽²⁾	-0.5	4.6	V	
Vo	Voltage applied to any output in the high-impeda	Voltage applied to any output in the high-impedance or power-off state (2)			V
Vo	Output voltage in the high or low state (2)			V _{CC} + 0.5	V
I _{IK}	Input clamp current	V _I < 0		- 50	mA
I _{OK}	Output clamp current	V _O < 0		- 50	mA
Io	Continuous output current			±20	mA
	Continuous current through V _{CC} or GND			±50	mA
TJ	Junction temperature			150	°C
T _{stg}	Storage temperature		-65	150	°C

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

			VALUE	UNIT
		Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 (1)	2000	
V _(ESD)	Electrostatic discharge	Charged-device model (CDM), per JEDEC specification JESD22-C101 ⁽²⁾	1000	V

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT		
V_{CC}	Supply voltage		0.8	3.6	V		
V_{I}	Input voltage		0	3.6	V		
Vo	Output voltage		0	V_{CC}	V		
		V _{CC} = 0.8 V		-20	μΑ		
		V _{CC} = 1.1 V		-1.1			
	High-level output current	V _{CC} = 1.4 V		-1.7	mA		
I _{OH}	riigii-level output current	V _{CC} = 1.65		-1.9			
		V _{CC} = 2.3 V		-3.1			
		V _{CC} = 3 V		-4			
		V _{CC} = 0.8 V		20	μΑ		
		V _{CC} = 1.1 V		1.1			
	Lave lavel autout average	V _{CC} = 1.4 V		1.7			
l _{OL}	Low-level output current	V _{CC} = 1.65 V		1.9	mA		
		V _{CC} = 2.3 V		3.1			
		V _{CC} = 3 V		4			
T _A	Operating free-air temperature		-40	85	°C		

All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. See the TI application report Implications of Slow or Floating CMOS Inputs, SCBA004.

Product Folder Links: SN74AUP1G57

⁽²⁾ The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.

⁽²⁾ JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



6.4 Thermal Information

		SN74AUP1G57						
THERMAL METRIC ⁽¹⁾		DBV (SOT-23)	DCK (SC70)	DRL (SOT)	DSF (SON)	DRY (SON)	YFP/YZP (DSBGA)	UNIT
		6 PINS	6 PINS	6 PINS	6 PINS	6 PINS	6 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	165	259	142	300	234	123	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report, SPRA953.

6.5 Electrical Characteristics

over operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V	T _A	= 25°C	T _A = -40	°C to 85°C	UNIT	
PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP M	AX MIN	MAX	UNIT	
		0.8 V	0.3		0.6 0.3	0.6		
V		1.1 V	0.53	1	0.9 0.53	0.9		
V _{T+} Positive-going		1.4 V	0.74	1	.11 0.74	1.11		
input threshold		1.65 V	0.91	1	.29 0.91	1.29	V	
voltage		2.3 V	1.37	1	.77 1.37	1.77		
		3 V	1.88	2	.29 1.88	2.29		
		0.8 V	0.1	1	0.6 0.1	0.6		
		1.1 V	0.26	0	.65 0.26	0.65		
V _{T-} Negative-going		1.4 V	0.39	0	.75 0.39	0.75	.,	
input threshold		1.65 V	0.47	0	.84 0.47	0.84	V	
voltage		2.3 V	0.69	1	.04 0.69	1.04		
		3 V	0.88	1	.24 0.88	1.24		
		0.8 V	0.07		0.5 0.07	0.5		
		1.1 V	0.08	0	.46 0.08	0.46		
$\begin{array}{l} \Delta V_T \\ \text{Hysteresis} \\ (V_{T+} - V_{T-}) \end{array}$		1.4 V	0.18	0	.56 0.18	0.56		
		1.65 V	0.27	0	.66 0.27		V	
		2.3 V	0.53	0	.92 0.53	0.92		
		3 V	0.79	1	.31 0.79	1.31		
	I _{OH} = -20 μA	0.8 V to 3.6 V	V _{CC} - 0.1		V _{CC} - 0.1			
	I _{OH} = -1.1 mA	1.1 V	$0.75 \times V_{CC}$ $0.7 \times V_{CC}$					
	I _{OH} = -1.7 mA	1.4 V	1.11		1.03			
	I _{OH} = -1.9 mA	1.65 V	1.32		1.3			
V_{OH}	I _{OH} = -2.3 mA		2.05		1.97		V	
	I _{OH} = -3.1 mA	2.3 V	1.9		1.85			
	I _{OH} = -2.7 mA	211	2.72		2.67			
	I _{OH} = -4 mA	3 V	2.6		2.55			
	I _{OL} = 20 μA	0.8 V to 3.6 V			0.1	0.1		
	I _{OL} = 1.1 mA	1.1 V			3 × ′cc	0.3 × V _{CC}		
	I _{OL} = 1.7 mA	1.4 V		0	.31	0.37		
V_{OL}	I _{OL} = 1.9 mA	1.65 V		0	.31	0.35	V	
JL .	I _{OL} = 2.3 mA	0.01/		0	.31	0.33		
	I _{OL} = 3.1 mA	2.3 V		0	.44	0.45		
	I _{OL} = 2.7 mA	0.1/		0	.31	0.33		
	I _{OL} = 4 mA	3 V		0	.44	0.45		
I _I (all inputs)	$V_I = GND \text{ to } 3.6 \text{ V}$	0 V to 3.6 V			0.1	0.5	μΑ	
I _{off}	V_{I} or $V_{O} = 0 \text{ V to } 3.6 \text{ V}$	0 V			0.2	0.6	μA	

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Electrical Characteristics (continued)

over operating free-air temperature range (unless otherwise noted)

DADAMETER	TEST CONDITIONS	V	T _A = 25°C		$T_A = -40^{\circ}C$ to 8	85°C	UNIT
PARAMETER	TEST CONDITIONS	V _{CC}	MIN TYP	MAX	MIN	MAX	UNIT
ΔI_{off}	V_I or $V_O = 0$ V to 3.6 V	0 V to 0.2 V		0.2		0.6	μΑ
I _{CC}	$V_I = GND \text{ or } (V_{CC} \text{ to } 3.6 \text{ V}), I_O =$	0.8 V to 3.6 V		0.5		0.9	μΑ
ΔI_{CC}	$V_I = V_{CC} - 0.6 V^{(1)}, I_O =$	= 0 3.3 V		40		50	μΑ
C	$V_I = V_{CC}$ or GND	0 V	1.5				pF
C _i	VI = VCC OI GIVD	3.6 V	1.5				рг
Co	$V_O = GND$	0 V	3				pF

⁽¹⁾ One input at V_{CC} – 0.6 V, other inputs at V_{CC} or GND.

6.6 Switching Characteristics, $C_L = 5 pF$

over recommended operating free-air temperature range, $C_L = 5 pF$ (unless otherwise noted) (see Figure 2 and Figure 3)

DADAMETED	FROM (INPUT)	TO (OUTPUT)	V _{cc}	T _A = 25°C			T _A = -40°C	LINUT	
PARAMETER				MIN	TYP	MAX	MIN	MAX	UNIT
		Y	0.8 V		28.6				
			1.2 V ± 0.1 V	2.6	9.5	13.6	2.1	17.1	
	In0, In1, or In2		1.5 V ± 0.1 V	1.9	6.4	9.1	1.4	11.1	no
t _{pd}	1110, 1111, 01 1112		1.8 V ± 0.15 V	1.4	5.2	7.1	0.9	8.9	ns
			2.5 V ± 0.2 V	1.1	3.6	5.3	0.6	6.3	
			3.3 V ± 0.3 V	1	2.9	4.4	0.5	5.3	

6.7 Switching Characteristics, $C_L = 10 \text{ pF}$

over recommended operating free-air temperature range, C_L = 10 pF (unless otherwise noted) (see Figure 2 and Figure 3)

DADAMETED	FROM	TO (OUTPUT)	V _{CC}	T _A = 25°C			$T_A = -40$ °C to 85°C		UNIT
PARAMETER	(INPUT)			MIN	TYP	MAX	MIN	MAX	UNII
			0.8 V		32.8				
		Y	1.2 V ± 0.1 V	2.6	11	15.1	2.1	18.1	
	In0 In1 or In0		1.5 V ± 0.1 V	1.9	7.4	10.3	1.4	12.4	
t _{pd}	In0, In1, or In2		1.8 V ± 0.15 V	1.4	6	8.1	0.9	10	ns
			2.5 V ± 0.2 V	1.1	4.3	6.1	0.6	7.3	
		3.3 V ± 0.3 V	1	3.5	5.1	0.5	6.1		

6.8 Switching Characteristics, $C_L = 15 pF$

over recommended operating free-air temperature range, C_L = 15 pF (unless otherwise noted) (see Figure 2 and Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{cc}	T _A = 25°C			$T_A = -40^{\circ}C t$		
				MIN	TYP	MAX	MIN	MAX	UNIT
			0.8 V		37				
		Y	1.2 V ± 0.1 V	3.6	12.3	16.8	3.1	20.1	
	In0 In1 or In0		1.5 V ± 0.1 V	2.8	8.3	11.4	2.3	13.7	
t _{pd}	ln0, ln1, or ln2		1.8 V ± 0.15 V	2.1	6.7	9	1.6	11.1	ns
			2.5 V ± 0.2 V	1.7	4.9	6.8	1.2	8.1	
			3.3 V ± 0.3 V	1.5	3.9	5.6	1	6.7	

Product Folder Links: SN74AUP1G57



6.9 Switching Characteristics, $C_L = 30 pF$

over recommended operating free-air temperature range, $C_L = 30 \text{ pF}$ (unless otherwise noted) (see Figure 2 and Figure 3)

PARAMETER	FROM	то	V	T,	_λ = 25°C		$T_A = -40^{\circ}C$	to 85°C	UNIT
PARAMETER	(INPUT)	(OUTPUT)	V _{CC}	MIN	TYP	MAX	MIN	MAX	UNII
			0.8 V		49.3				
	In0, In1, or In2		1.2 V ± 0.1 V	5	15.7	21.4	4.5	26.5	
		Y	1.5 V ± 0.1 V	3.9	10.8	14.4	3.4	17.4	20
t _{pd}			1.8 V ± 0.15 V	3.1	8.8	11.4	2.6	14	ns
			2.5 V ± 0.2 V	2.6	6.4	8.4	2.1	10.1	
			3.3 V ± 0.3 V	2.3	5.3	7	1.8	8.4	

6.10 Operating Characteristics

 $T_A = 25$ °C

	PARAMETER	TEST CONDITIONS	V _{cc}	TYP	UNIT	
			0.8 V	4		
			1.2 V ± 0.1 V	4		
0	Davis dissination consitons	f 40 MH-	1.5 V ± 0.1 V	4	pF	
C _{pd}	Power dissipation capacitance	f = 10 MHz	1.8 V ± 0.15 V	4		
			2.5 V ± 0.2 V	4.1		
			3.3 V ± 0.3 V	4.3		

6.11 Typical Characteristics

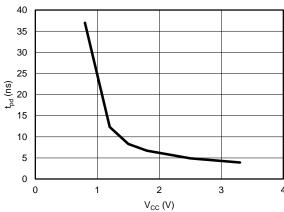


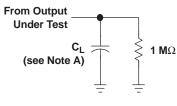
Figure 1. t_{pd} vs V_{CC}, 15-pF Load

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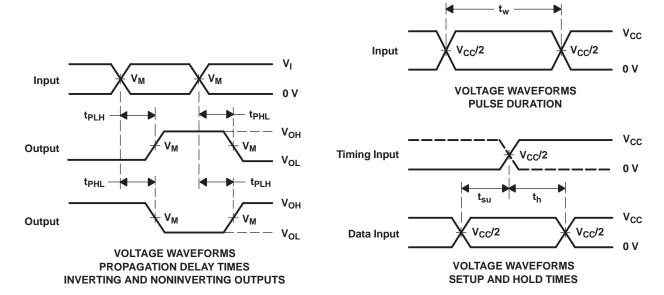
7 Parameter Measurement Information

7.1 Propagation Delays, Setup and Hold Times, and Pulse Duration



LOAD CIRCUIT

	V _{CC} = 0.8 V	V _{CC} = 1.2 V ± 0.1 V	V _{CC} = 1.5 V ± 0.1 V	V _{CC} = 1.8 V ± 0.15 V	V_{CC} = 2.5 V \pm 0.2 V	V _{CC} = 3.3 V ± 0.3 V
C _L V _M	5, 10, 15, 30 pF V _{CC} /2 V _{CC}	5, 10, 15, 30 pF V _{CC} /2 V _{CC}	5, 10, 15, 30 pF V _{CC} /2 V _{CC}	5, 10, 15, 30 pF V _{CC} /2 V _{CC}	5, 10, 15, 30 pF V _{CC} /2 V _{CC}	5, 10, 15, 30 pF V _{CC} /2 V _{CC}



NOTES: A. C_L includes probe and jig capacitance.

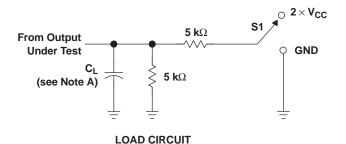
- B. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \Omega$, slew rate \geq 1 V/ns.
- C. The outputs are measured one at a time, with one transition per measurement.
- D. t_{PLH} and t_{PHL} are the same as t_{pd} .
- E. All parameters and waveforms are not applicable to all devices.

Figure 2. Load Circuit and Voltage Waveforms

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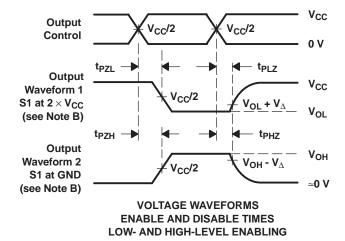


7.2 Enable and Disable Times



TEST	S1
t _{PLZ} /t _{PZL}	2×V _{CC}
t _{PHZ} /t _{PZH}	GND

	V _{CC} = 0.8 V	V _{CC} = 1.2 V ± 0.1 V	V _{CC} = 1.5 V ± 0.1 V	V _{CC} = 1.8 V ± 0.15 V	V_{CC} = 2.5 V \pm 0.2 V	V _{CC} = 3.3 V ± 0.3 V
CL	5, 10, 15, 30 pF	5, 10, 15, 30 pF	5, 10, 15, 30 pF	5, 10, 15, 30 pF	5, 10, 15, 30 pF	5, 10, 15, 30 pF
V _M	V _{CC} /2	V _{CC} /2	V _{CC} /2	V _{CC} /2	V _{CC} /2	V _{CC} /2
VI	V _{CC}	V _{CC}	V _{CC}	V _{CC}	V _{CC}	V _{CC}
V_Δ	0.1 V	0.1 V	0.1 V	0.15 V	0.15 V	0.3 V



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_0 = 50 \Omega$, slew rate \geq 1 V/ns.
- D. The outputs are measured one at a time, with one transition per measurement.
- E. t_{PLZ} and t_{PHZ} are the same as t_{dis}.
- F. t_{PZL} and t_{PZH} are the same as t_{en}.
- G. All parameters and waveforms are not applicable to all devices.

Figure 3. Load Circuit and Voltage Waveforms

Product Folder Links: SN74AUP1G57



8 Detailed Description

8.1 Overview

The AUP family is Tl's premier solution to the low-power needs of the industry in battery-powered portable applications. This family ensures a very low static and dynamic power consumption across the entire V_{CC} range of 0.8 V to 3.6 V, resulting in an increased battery life. This product also maintains excellent signal integrity, which produces very low undershoot and overshoot characteristics.

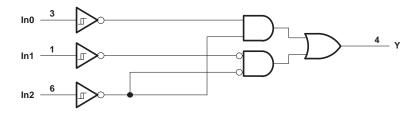
The SN74AUP1G57 features configurable multiple functions. The output state is determined by eight patterns of 3-bit input. The user can choose the logic functions AND, OR, NAND, NOR, XNOR, inverter, and noninverter. All inputs can be connected to V_{CC} or GND.

The device functions as an independent gate with Schmitt-trigger inputs, which allow for slow input transition and better switching noise immunity at the input.

NanoStar package technology is a major breakthrough in IC packaging concepts, using the die as the package.

This device is fully specified for partial-power-down applications using I_{off}. The I_{off} circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

8.2 Functional Block Diagram



8.3 Feature Description

This part is available in the TI NanoStar package. It has low static-power consumption with $I_{CC} = 0.9 \mu A$ maximum and low dynamic power consumption ($C_{pd} = 4.3 pF$, Typical at 3.3 V).

The inputs have low capacitance, with typical $C_i = 1.5 \text{ pF}$.

This part has low noise, with overshoot and undershoot less than 10% of V_{CC}.

This part supports partial-power-down mode operation. When this part is powered down ($V_{CC} = 0 \text{ V}$), the leakage current into the device is characterized by I_{off} .

Schmitt-trigger inputs provide hysterisis and consistency in V_{IH} / V_{II} .

It has a wide operating V_{CC} range of 0.8 V to 3.6 V, and has been optimized for 3.3-V operation.

3.6-V I/O tolerant to support mixed-mode signal operation.

It has a low propagation delay of 5.3 ns at 3.3 V.

It is suitable for point-to-point applications.

8.4 Device Functional Modes

Table 1 lists all the functional modes of the SN74AUP1G57.

Table 1. Function Table

	INPUTS	OUTPUT			
ln2	In1	In0	Υ		
L	L	L	Н		
L	L	Н	L		
L	Н	L	Н		

Product Folder Links: SN74AUP1G57



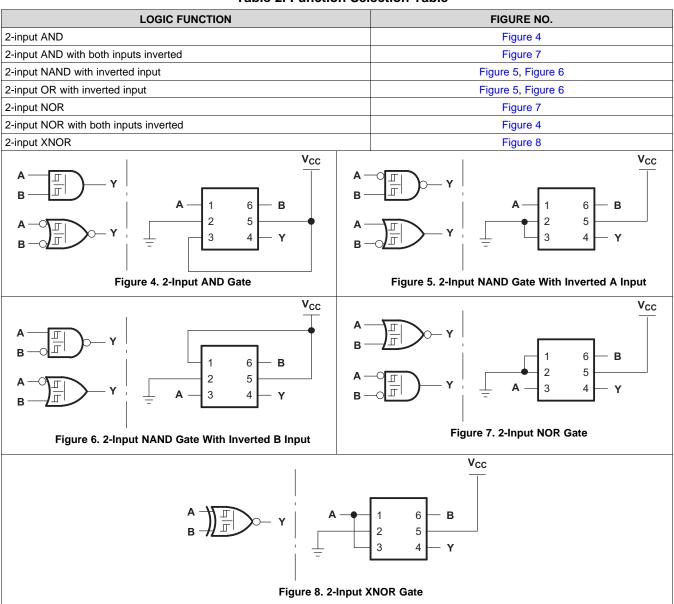
Table 1. Function Table (continued)

	INPUTS	OUTPUT	
ln2	In1	In0	Υ
L	Н	Н	L
Н	L	L	L
Н	L	Н	L
Н	Н	L	Н
Н	Н	Н	Н

8.4.1 Logic Configurations

Table 2 lists all the logic functions of the SN74AUP1G57.

Table 2. Function Selection Table



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9 Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

9.1 Application Information

The SN74AUP1G57 features configurable multiple functions. The output state is determined by eight patterns of 3-bit input. The user can choose the logic functions AND, NAND, NOR, XNOR, inverter, and noninverter. All inputs can be connected to V_{CC} or GND.

This part can be used in any application where an equivalent single gate would work. The biggest benefit to this part is that it can be used for multiple functions on the same board, reducing the total number of part numbers to be used.

9.2 Typical Application

This application shows how the SN74AUP1G57 can be configured to work as an AND logic gate. This part can The capacitor shown is 0.1 uF and should be placed as close as possible to the part.

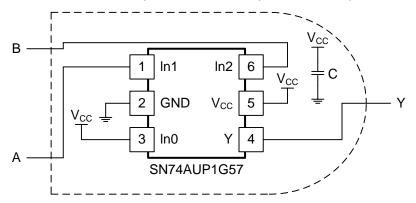


Figure 9. Schematic for AND Gate Configuration of SN74AUP1G57

9.2.1 Design Requirements

This device uses CMOS technology and has balanced output drive. Take care to avoid bus contention because it can drive currents that would exceed maximum limits.

9.2.2 Detailed Design Procedure

- 1. Recommended Input conditions
 - Rise time and fall time specs. See (Δt/ΔV) in Recommended Operating Conditions
 - Specified high and low levels. See (V_{IH} and V_{IL}) in Recommended Operating Conditions
 - Inputs are overvoltage tolerant allowing them to go as high as 4.6 V at any valid $V_{\rm CC}$
- 2. Recommend output conditions
 - Load currents should not exceed 20 mA on the output and 50 mA total for the part
 - Outputs should not be pulled above V_{CC} + 0.5 V.

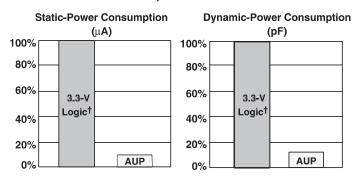
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Typical Application (continued)

9.2.3 Application Curve

The AUP family of single gate logic makes excellent translators for the new lower voltage microprocessors that typically are powered from 0.8 V to 1.2 V. They can drop the voltage of peripheral drivers and accessories that are still powered by 3.3 V to the new microcontroller power levels.



[†] Single, dual, and triple gates.

Figure 10. AUP - The Lowest-Power Family

10 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*.

Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. For devices with a single supply, a 0.1- μ F bypass capacitor is recommended. If there are multiple pins labeled V_{CC} , then a 0.01- μ F or 0.022- μ F capacitor is recommended for each V_{CC} because the V_{CC} pins will be tied together internally. For devices with dual supply pins operating at different voltages, for example V_{CC} and V_{DD} , a 0.1- μ F bypass capacitor is recommended for each supply pin. It is acceptable to parallel multiple bypass capacitors to reject different frequencies of noise. 0.1- μ F and 1- μ F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

11 Layout

11.1 Layout Guidelines

Reflections and matching are closely related to the loop antenna theory but are different enough to be discussed separately from the theory. When a PCB trace turns a corner at a 90° angle, a reflection can occur. A reflection occurs primarily because of the change of width of the trace. At the apex of the turn, the trace width increases to 1.414 times the width. This increase upsets the transmission-line characteristics, especially the distributed capacitance and self–inductance of the trace which results in the reflection. Not all PCB traces can be straight and therefore some traces must turn corners. Figure 11 shows progressively better techniques of rounding corners. Only the last example (BEST) maintains constant trace width and minimizes reflections.

Product Folder Links: SN74AUP1G57

11.2 Layout Example

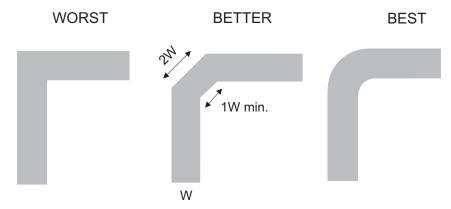


Figure 11. Trace Example

12 Device and Documentation Support

12.1 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community TI's Engineer-to-Engineer (E2E) Community. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

12.2 Trademarks

NanoStar, E2E are trademarks of Texas Instruments.
All other trademarks are the property of their respective owners.

12.3 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

12.4 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

Product Folder Links: SN74AUP1G57

17-Jun-2025

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PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
						(4)	(5)		
SN74AUP1G57DBVR	Active	Production	SOT-23 (DBV) 6	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HA7R
SN74AUP1G57DBVR.B	Active	Production	SOT-23 (DBV) 6	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HA7R
SN74AUP1G57DBVT	Active	Production	SOT-23 (DBV) 6	250 SMALL T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HA7R
SN74AUP1G57DBVT.B	Active	Production	SOT-23 (DBV) 6	250 SMALL T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HA7R
SN74AUP1G57DCKR	Active	Production	SC70 (DCK) 6	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HHR
SN74AUP1G57DCKR.B	Active	Production	SC70 (DCK) 6	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HHR
SN74AUP1G57DCKRE4	Active	Production	SC70 (DCK) 6	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HHR
SN74AUP1G57DCKT	Active	Production	SC70 (DCK) 6	250 SMALL T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HHR
SN74AUP1G57DCKT.B	Active	Production	SC70 (DCK) 6	250 SMALL T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HHR
SN74AUP1G57DRLR	Active	Production	SOT-5X3 (DRL) 6	4000 LARGE T&R	Yes	NIPDAU NIPDAUAG	Level-1-260C-UNLIM	-40 to 85	(1KC, HH7, HHR)
SN74AUP1G57DRLR.B	Active	Production	SOT-5X3 (DRL) 6	4000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	(1KC, HH7, HHR)
SN74AUP1G57DRYR	Active	Production	SON (DRY) 6	5000 LARGE T&R	Yes	NIPDAU NIPDAUAG	Level-1-260C-UNLIM	-40 to 85	HH
SN74AUP1G57DRYR.B	Active	Production	SON (DRY) 6	5000 LARGE T&R	Yes	NIPDAUAG	Level-1-260C-UNLIM	-40 to 85	HH
SN74AUP1G57DRYRG4	Active	Production	SON (DRY) 6	5000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HH
SN74AUP1G57DRYRG4.B	Active	Production	SON (DRY) 6	5000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HH
SN74AUP1G57DSFR	Active	Production	SON (DSF) 6	5000 LARGE T&R	Yes	NIPDAU NIPDAUAG NIPDAU	Level-1-260C-UNLIM	-40 to 85	НН
SN74AUP1G57DSFR.B	Active	Production	SON (DSF) 6	5000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HH
SN74AUP1G57YZPR	Active	Production	DSBGA (YZP) 6	3000 LARGE T&R	Yes	SNAGCU	Level-1-260C-UNLIM	-40 to 85	HHN
SN74AUP1G57YZPR.B	Active	Production	DSBGA (YZP) 6	3000 LARGE T&R	Yes	SNAGCU	Level-1-260C-UNLIM	-40 to 85	HHN

⁽¹⁾ Status: For more details on status, see our product life cycle.

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.



PACKAGE OPTION ADDENDUM

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(5) MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

(6) Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74AUP1G57DBVR	SOT-23	DBV	6	3000	180.0	8.4	3.23	3.17	1.37	4.0	8.0	Q3
SN74AUP1G57DBVT	SOT-23	DBV	6	250	180.0	8.4	3.23	3.17	1.37	4.0	8.0	Q3
SN74AUP1G57DCKR	SC70	DCK	6	3000	180.0	8.4	2.41	2.41	1.2	4.0	8.0	Q3
SN74AUP1G57DCKT	SC70	DCK	6	250	180.0	8.4	2.41	2.41	1.2	4.0	8.0	Q3
SN74AUP1G57DRLR	SOT-5X3	DRL	6	4000	180.0	8.4	2.0	1.8	0.75	4.0	8.0	Q3
SN74AUP1G57DRYR	SON	DRY	6	5000	180.0	9.5	1.15	1.6	0.75	4.0	8.0	Q1
SN74AUP1G57DRYRG4	SON	DRY	6	5000	180.0	9.5	1.15	1.6	0.75	4.0	8.0	Q1
SN74AUP1G57DSFR	SON	DSF	6	5000	180.0	8.4	1.16	1.16	0.5	4.0	8.0	Q2
SN74AUP1G57YZPR	DSBGA	YZP	6	3000	178.0	9.2	1.02	1.52	0.63	4.0	8.0	Q1



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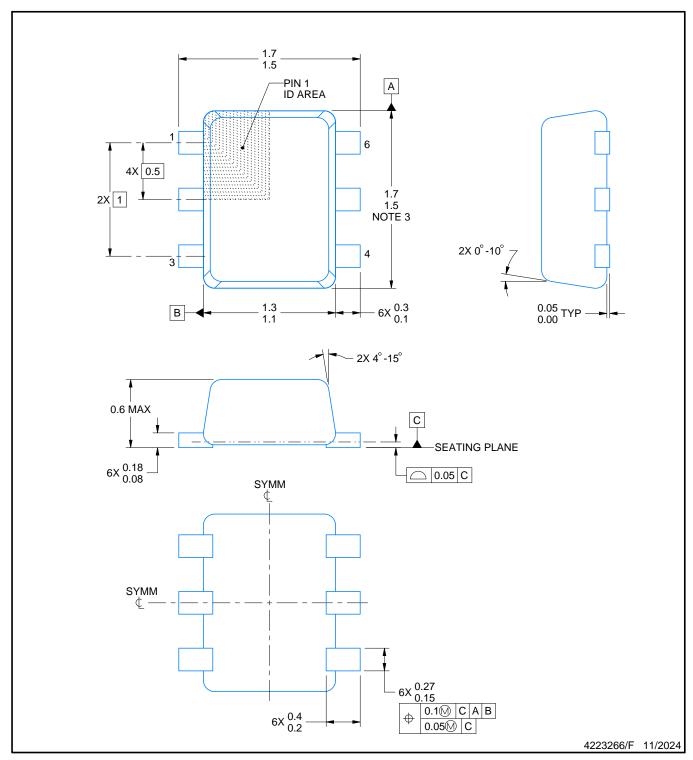


*All dimensions are nominal

7 III dimensions are nominal							
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74AUP1G57DBVR	SOT-23	DBV	6	3000	202.0	201.0	28.0
SN74AUP1G57DBVT	SOT-23	DBV	6	250	202.0	201.0	28.0
SN74AUP1G57DCKR	SC70	DCK	6	3000	202.0	201.0	28.0
SN74AUP1G57DCKT	SC70	DCK	6	250	202.0	201.0	28.0
SN74AUP1G57DRLR	SOT-5X3	DRL	6	4000	210.0	185.0	35.0
SN74AUP1G57DRYR	SON	DRY	6	5000	184.0	184.0	19.0
SN74AUP1G57DRYRG4	SON	DRY	6	5000	184.0	184.0	19.0
SN74AUP1G57DSFR	SON	DSF	6	5000	210.0	185.0	35.0
SN74AUP1G57YZPR	DSBGA	YZP	6	3000	220.0	220.0	35.0



PLASTIC SMALL OUTLINE



NOTES:

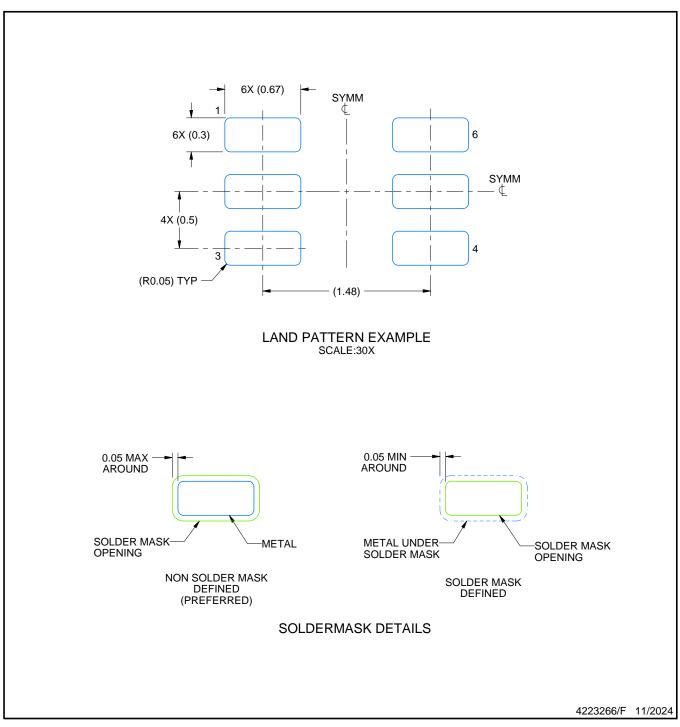
- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
 4. Reference JEDEC registration MO-293 Variation UAAD



PLASTIC SMALL OUTLINE

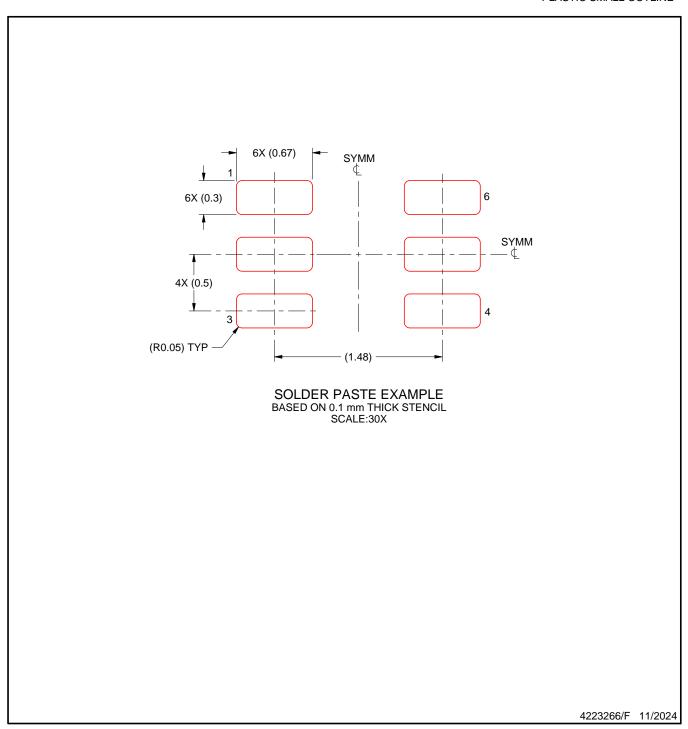


NOTES: (continued)

- 5. Publication IPC-7351 may have alternate designs.
- 6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.7. Land pattern design aligns to IPC-610, Bottom Termination Component (BTC) solder joint inspection criteria.



PLASTIC SMALL OUTLINE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.







NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.25 per side.

- 4. Leads 1,2,3 may be wider than leads 4,5,6 for package orientation.
- 5. Refernce JEDEC MO-178.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





DIE SIZE BALL GRID ARRAY



NOTES:

NanoFree Is a trademark of Texas Instruments.

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.
- 3. NanoFree[™] package configuration.



DIE SIZE BALL GRID ARRAY



NOTES: (continued)

4. Final dimensions may vary due to manufacturing tolerance considerations and also routing constraints. For more information, see Texas Instruments literature number SBVA017 (www.ti.com/lit/sbva017).



DIE SIZE BALL GRID ARRAY



NOTES: (continued)

5. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release.







NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.15 per side.

 4. Falls within JEDEC MO-203 variation AB.





NOTES: (continued)

5. Publication IPC-7351 may have alternate designs.

6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.





Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.









NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.





NOTES: (continued)

3. For more information, see QFN/SON PCB application report in literature No. SLUA271 (www.ti.com/lit/slua271).





NOTES: (continued)

Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.







NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. Reference JEDEC registration MO-287, variation X2AAF.





NOTES: (continued)

4. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).





4. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



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